

REMARKS/ARGUMENTS

Claims 2-4 and 32-34 are currently pending in this case, claims 1 and 5-31 having been canceled without prejudice and claims 32-34 having been added by this paper.

Rejection of the Claims

The Examiner has rejected claims 2-4 pursuant to 35 U.S.C. §102(e) as being anticipated by U.S. Patent No. 6,119,255 (Akram) or U.S. Patent No. 6,300,785 (Cook). In response thereto, the Applicant has amended claim 2 to read as follows:

2. A method of testing an electronic device on a wafer, comprising:  
    providing an electronic device for use in an optical communications system after the electronic device is packaged with an associated photo detector;  
    providing a test photo detector having electrical characteristics similar to the associated photo detector; and  
    prior to packaging the electronic device with the associated photo detector, detecting defects in the electronic device using the test photo detector by:  
        generating an optical test signal;  
        providing the optical test signal to the test photo detector; and  
        supplying an electrical output of the test photo detector to the electronic device on the wafer.

The Applicant respectfully directs the Examiner's attention to the limitations "providing a test photo detector having electrical characteristics similar to the associated photo detector" and "prior to packaging the electronic device with the associated photo detector, detecting defects in the electronic device using the test photo detector" of claim 2. Support for these features may be found, for example, in ¶¶ [0027], [0040], [0060], and [0061] of the Applicant's specification.

As stated in the Applicant's specification, an optical test signal may be provided to a first photo detector 28 and converted by the first photo detector 28 into an electrical output which is supplied to a die (e.g., electronic circuit) under test. (Application, ¶ [0060]). The photo detector 28 may be "matched to the type of photo detector with which the electronic circuit under test is designed to operate." (Application, ¶ [0061]). Therefore, the die or electronic circuit under test may be tested using a test photo detector (e.g., photo detector 28) prior to packaging the die or electronic circuit under test with an associated photo detector (e.g., a photo detector with which the electronic circuit under test is designed to operate). In this manner, defects in electronic circuitry may be detected prior to packaging. Neither the Akram patent nor the Cook patent discloses such a feature.

Rather, the Akram patent defines an integrated circuit (IC) as "including a package, a chip in the package having circuitry, and pins extending from the package and being connected to the circuitry." (Col. 4, lines 36-40). According to the Akram patent a receptacle 16 included in a burn-in test board 14 may receive the devices under test 12. (Col. 4, lines 54-56). Devices under test may include circuit cards and IC's. (Col. 4, lines 34-36). Therefore, the Akram patent appears to describe testing circuits only after packaging and not prior to packaging. For at least this reason, the Applicant respectfully submits that independent claim 2 is allowable over the Akram patent.


The Cook patent describes a structure and method for determining device parameters without physically probing a wafer. (Col. 1, lines 43-47). The Cook patent appears to describe a contactless probe that is included in a device to be tested (See, for example, Claim 1 of the Cook patent). However, the Cook patent does not appear to disclose providing a test photo

detector, which has electrical characteristics similar to another photo detector that is to be packaged with an electronic device, for detecting defects in the electronic device prior to packaging. For at least this reason, the Applicant respectfully submits that independent claim 2 is also allowable over the Cook patent.

Claims 3-4 and new claim 32 depend from claim 2 and are submitted as similarly allowable. Support for claim 32 may be found, for example, in ¶ [0064]. New claims 33-34 contain limitations that are similar to the limitations of claim 2. Therefore, all of the claims are believed to be in condition for allowance and passage to issue is respectfully solicited.

A separate Request for One Month Extension of Time is enclosed herewith, including authorization to charge deposit account no. 04-1696 for the extension fee. The Applicant does not believe any other fees are due regarding this amendment. If any fees are required, however, please charge Deposit Account No. 04-1696. The Applicant encourages the Examiner to telephone the Applicant's attorney to discuss the response should any issues remain.

Respectfully Submitted,



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